

SNRI2020 Lab Proposal

CMOS Cryogenic Readout Electronics

Scuola Nazionale dei Rivelatori Innovativi 2020

Kick-off Meeting

Torino

2019-11-22



Istituto Nazionale di Fisica Nucleare

Manuel Da Rocha Rolo

Why?

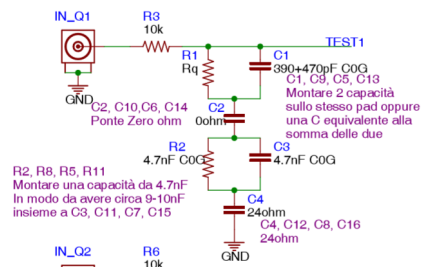
- * Cryogenic operation of CMOS is a rapidly growing field of interest**
- * Quantum computing (control and periphery electronics at 4K)**
- * Dark matter and neutrino experiments with LAr, LXe**
 - Darkside, ARGO (global DM dual-phase TPC 300-ton, >2027)**
 - DUNE, proto-DUNE**
 - nEXO**
 - ...**

Context of the ongoing activity

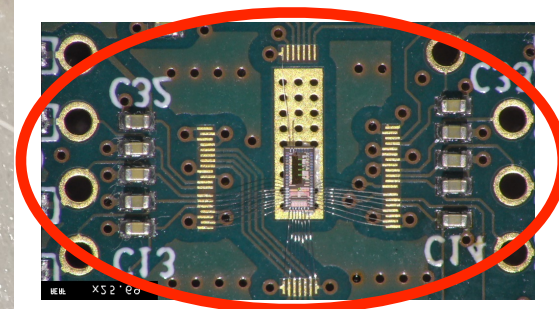
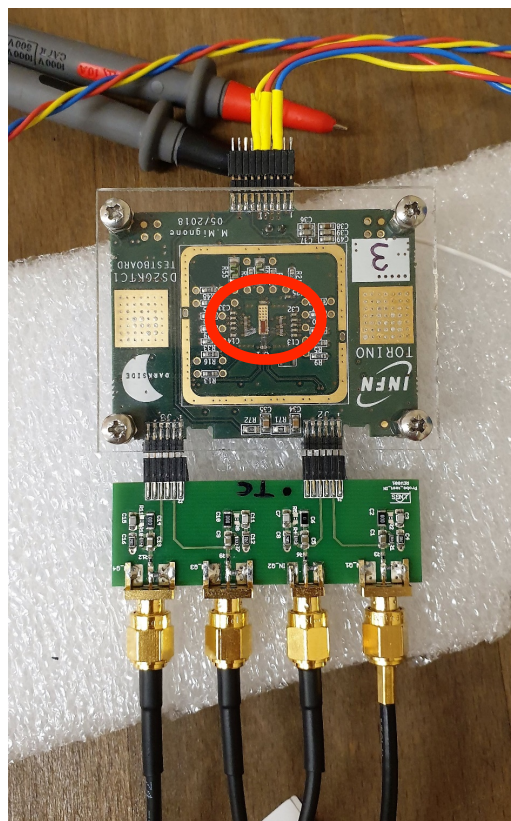
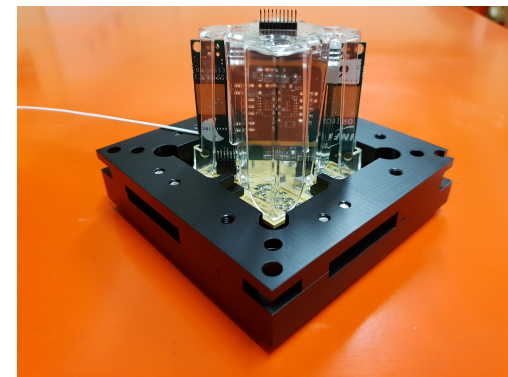


- * Activity at INFN-TO in the framework of Darkside
- * CMOS microelectronics development for cryogenic operation
- * Readout of large area SiPM tiles (24 cm²)
- * Developed 2 prototypes of front-end amplifier for operation at 87K
- * Laboratory proposal using ICs and associated FEBs, and SiPMs

Materials and Lab setup



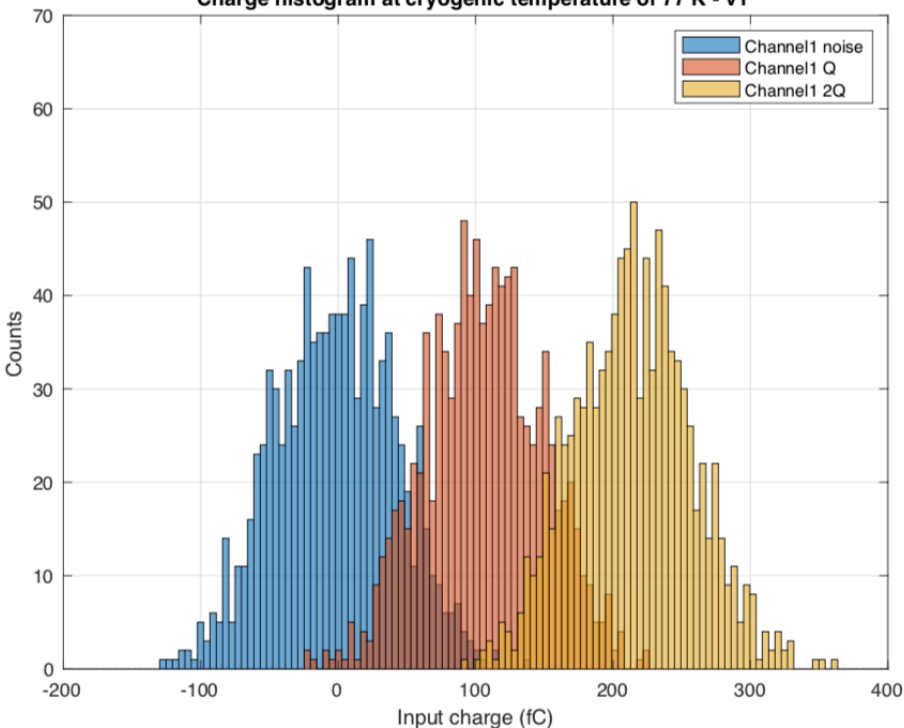
- LN2
- dewar
- oscilloscope
- test boards and load cards
- SiPM tiles
- laser and cryo fibre



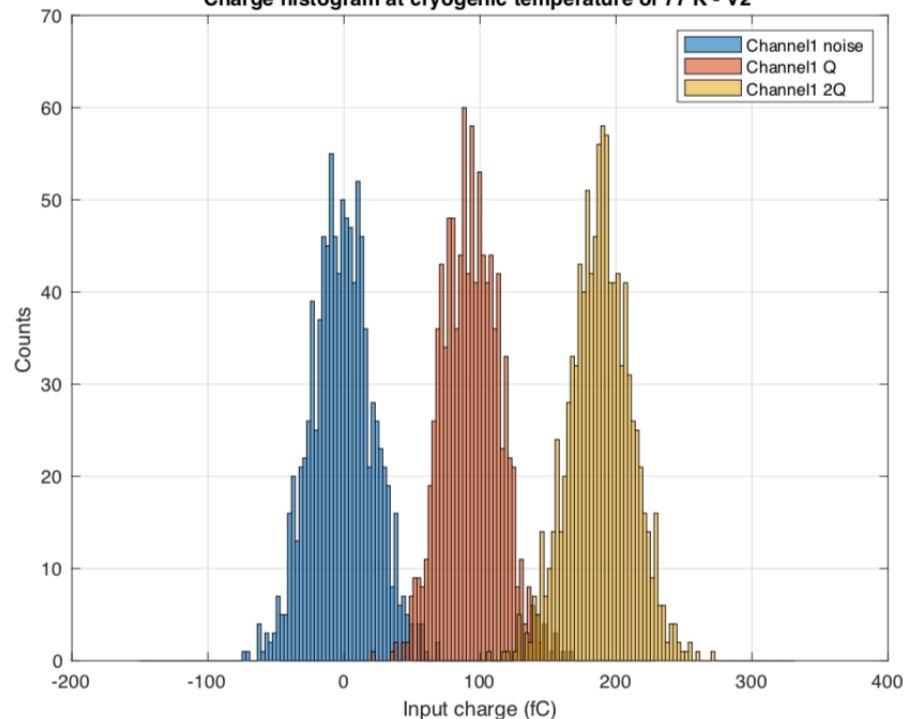
Proposed activity: electrical tests

- * Spectra of integrated output current signal of different amplifier designs, on a single channel, for a single p.e. $Q=95$ fC (charge injection board and programmable pulse generator)
- * Obtain the resulting charge histogram of channel 1 DS20K v1 (left) and DS20K v2 (right),

Charge histogram at cryogenic temperature of 77 K - v1



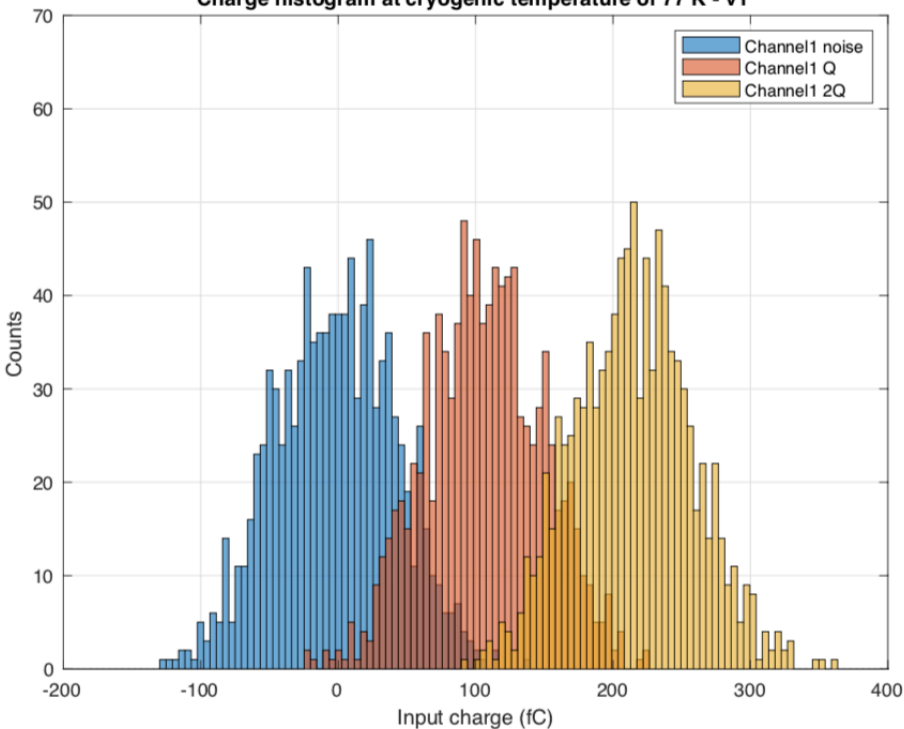
Charge histogram at cryogenic temperature of 77 K - V2



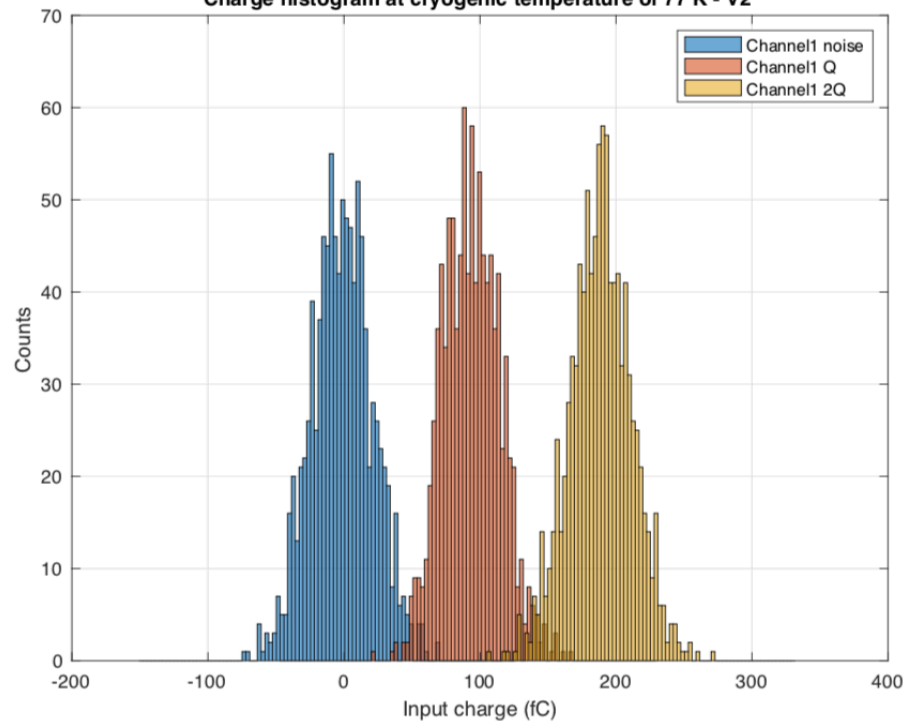
Proposed activity: electrical tests

- * Obtain spectra of output charge of different amplifiers using all channels at $Q=95\text{fC}$
- * Charge histogram of **all channels** V1 (left) and V2 (right), $N=3000$ samples.

Charge histogram at cryogenic temperature of 77 K - v1

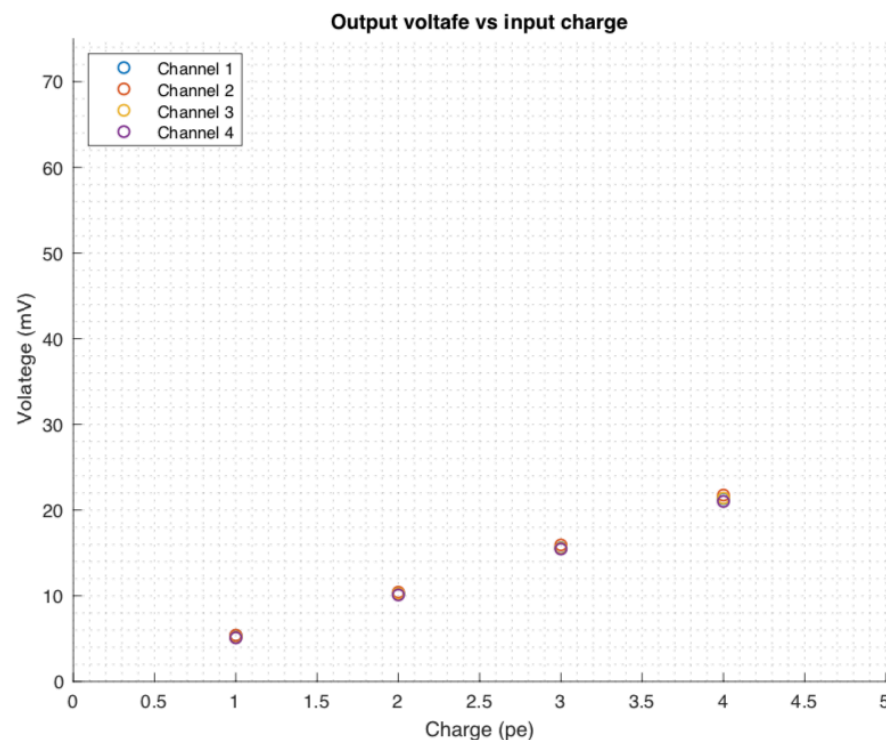
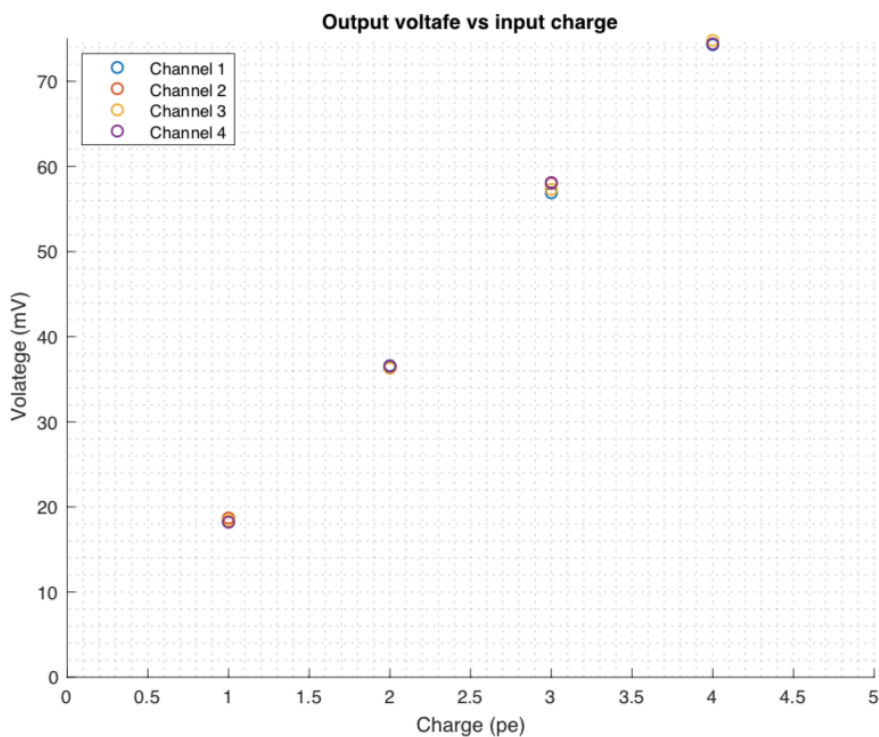


Charge histogram at cryogenic temperature of 77 K - V2

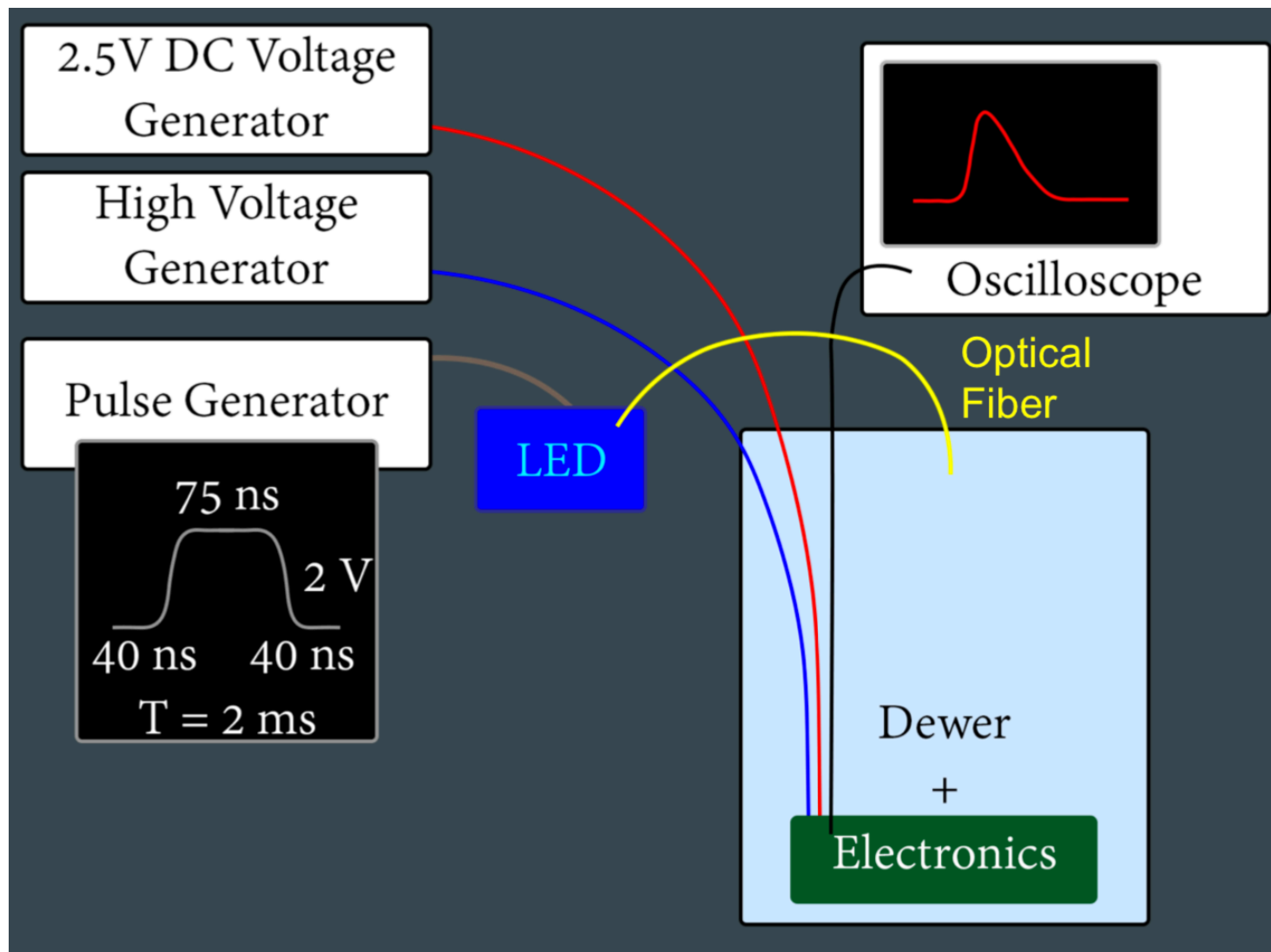


Proposed activity: electrical tests

- * Calculate the gain (measuring pulse height for 1-2-3-4 p.e.) at LN (77K) with a charge injection circuit and a test-pulse generator, comparison between different amplifiers

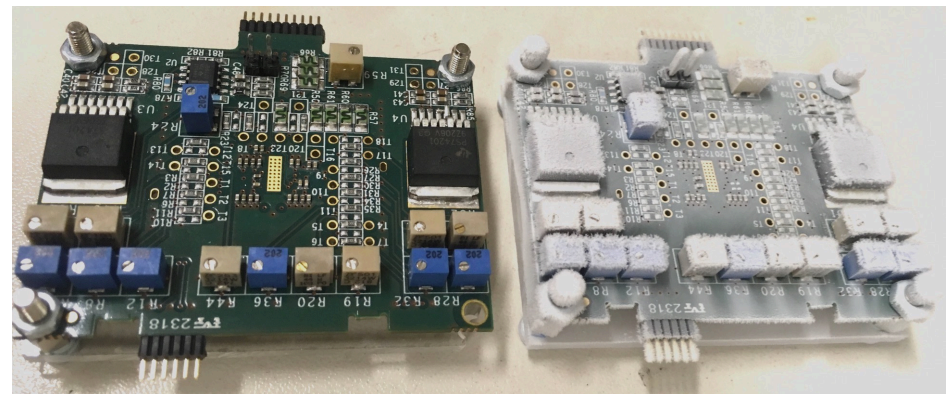
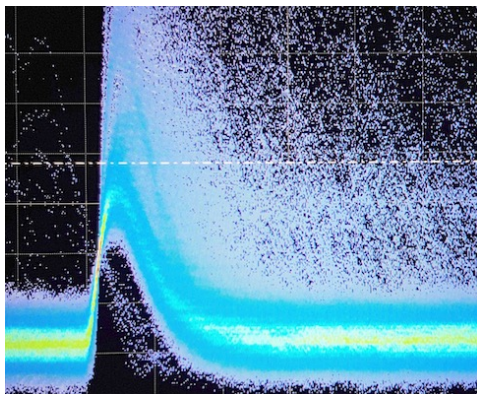


Proposed activity - tests with SiPMs

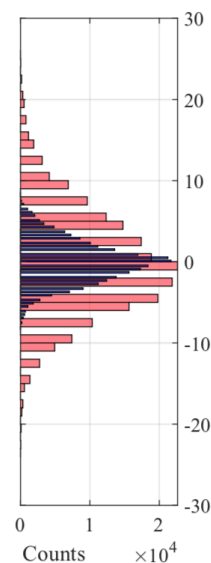
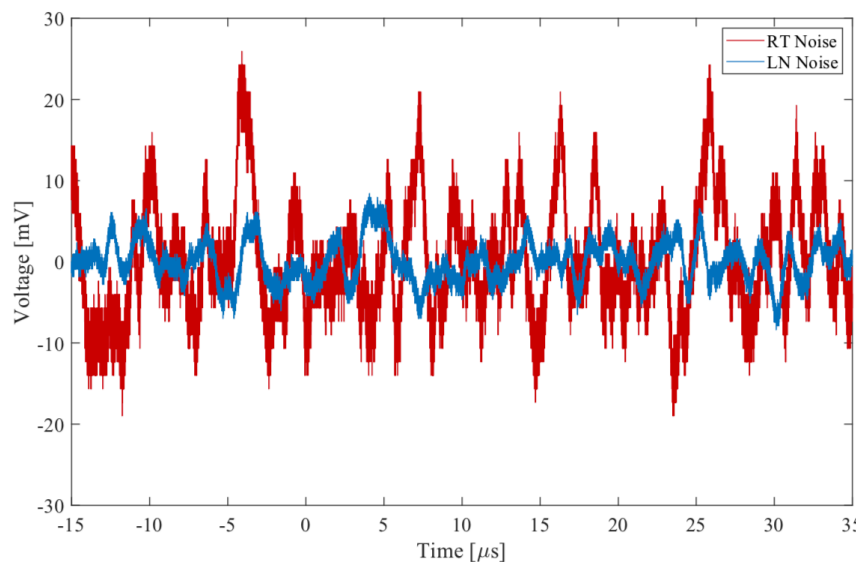


Proposed activity: basic tests with SiPMs

* Trigger on single-photon and measure r.m.s. at RT and LN



Noise $V_{RT} = 6.4 \text{ mV}$, $V_{LN} = 2.3 \text{ mV}$

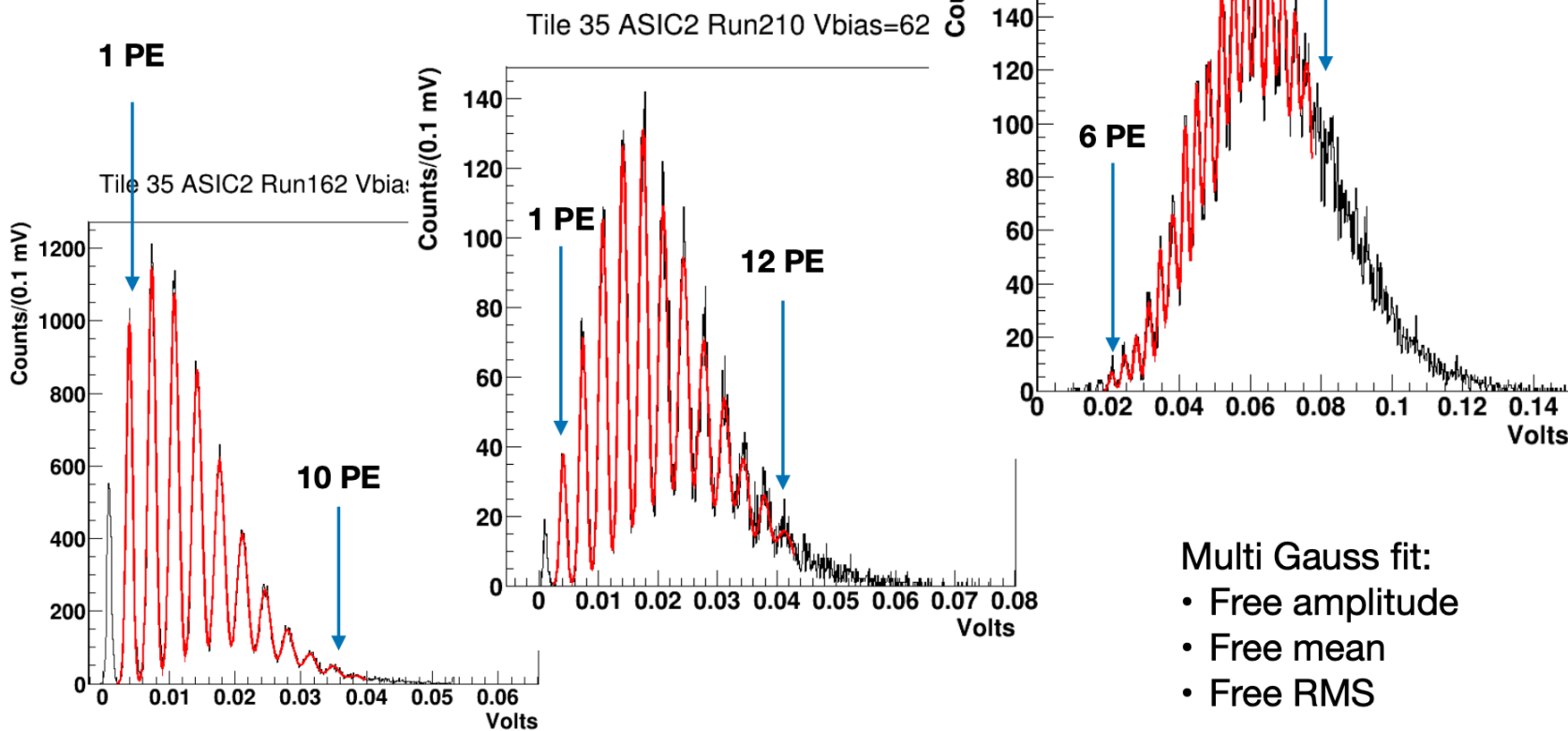


Proposed activity: SiPMs and laser tests

* multi-photon histograms (below, activity at INFN-GE - B. Bottino)

Fixed over voltage: 4 VoV \longrightarrow V bias = 62 V
Change laser power with fixed frequency \longrightarrow change the number of photons reaching the tile

Amplitude spectra with no filtering



Multi Gauss fit:

- Free amplitude
- Free mean
- Free RMS

Proposed activity: SiPMs and laser tests



*evaluate SNR as a function of OV (below, activity at INFN-GE - B. Bottino)

Bias Voltage	Over Voltage	1 PE peak	1 PE sigma	Noise RMS	SNR
62 V	4 V	3.43 mV	0.46 mV	0.46 mV	7.5
64 V	5 V	4.36 mV	0.50 mV	0.48 mV	8.7
66 V	6 V	5.30 mV	0.55 mV	0.48 mV	9.6
68 V	7 V	6.22 mV	0.60 mV	0.49 mV	10.4
70 V	8 V	7.06 mV	0.71 mV	0.54 mV	9.9

- *safe handling of LN:*
 - *important to clarify an appropriate concept of “hands-on approach” ...*
- *security and training of attendees*
- *protection (gloves, goggles)*
- *LN transportation and storage*